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**Yefremenko et al.**

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(54) **METHOD FOR DETECTION AND IMAGING  
OVER A BROAD SPECTRAL RANGE**

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**H01L 27/18** (2006.01)

(52) **U.S. Cl.** ..... **250/336.2**

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See application file for complete search history.

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(57) **ABSTRACT**

A method of controlling the coordinate sensitivity in a superconducting microbolometer employs localized light, heating or magnetic field effects to form normal or mixed state regions on a superconducting film and to control the spatial location. Electron beam lithography and wet chemical etching were applied as pattern transfer processes in epitaxial Y—Ba—Cu—O films. Two different sensor designs were tested: (i) a 3 millimeter long and 40 micrometer wide stripe and (ii) a 1.25 millimeters long, and 50 micron wide meandering-like structure. Scanning the laser beam along the stripe leads to physical displacement of the sensitive area, and, therefore, may be used as a basis for imaging over a broad spectral range. Forming the superconducting film as a meandering structure provides the equivalent of a two-dimensional detector array. Advantages of this approach are simplicity of detector fabrication, and simplicity of the read-out process requiring only two electrical terminals.

**25 Claims, 5 Drawing Sheets**

